

<b>Notice of References Cited</b>	Application/Control No. 10/564,503		Applicant(s)/Patent Under Reexamination KABU ET AL.	
	Examiner DAVID WEISZ		Art Unit 1797	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,057,482	05-2000	Okada et al.	568/705
	C	US-			
	D	US-			
	E	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	WO2002068378	09-2002	Japan	Ono et al.	
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	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	X	

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